

TAIC- PART 2013 PROGRAM

Date and Time: March 18, 2013 09:00-17:30

Location: Abbaye de Neumünster



09:00 - 10:00: Welcome and Keynote

- 09:00 Vladimir Entin, Sigrid Eldh, Michael Felderer, Nadia Alshahwan **"Welcome"**
- 09:15 Elaine Weyuker and Tom Ostrand (Visiting Scholar, DIMACS, Rutgers University) **Keynote: "Three Stories, Three Endings, Some Morals"**

10:00 - 10:30 Test Case Selection

- 10:00 Georg Buchgeher, Christian Ernstbrunner, Rudolf Ramler and Michael Lusser **"Towards Tool-Support for Test Case Selection in Manual Regression Testing"**

10:30 - 11:00: Coffee Break

11:00 - 12:30 Refactoring, Defect Localization and Reachability

- 11:00 Steve Counsell, Alessandro Murgia, Matt Gattrell, Rob Hierons, Giulio Concas, Michele Marchesi and Roberto Tonelli **"Conditional-based refactorings and fault-proneness: an empirical study"**
- 11:30 Anis Yousefi and Alan Wasssyng **"A Call Graph Mining and Matching Based Defect Localization Technique"**
- 12:00 Kumar Madhukar, Ravindra Metta, Priyanka Singh and Venkatesh R **"Reachability Verification of Rhapsody Statecharts"**

12:30 - 14:00: Lunch Break

14:00 - 15:30 Process, Organization and Maintainability

- 14:00 Anca Deak and Tor Stålhane **"Organization of testing activities in Norwegian Software Companies"**
- 14:30 Maurizio Leotta, Diego Clerissi, Filippo Ricca and Cristiano Spadaro **"Improving Test Suites Maintainability with the Page Object Pattern: an Industrial Case Study"**
- 15:00 Birgit Demuth, Harry Sneed and Bjoern Freitag **"A Process for Assessing Data Quality"**

15:30 - 16:00: Coffee Break

16:00 - 17:00: Fast Abstracts

- 16:00 Dominik Franke, Stefan Hempel and Stefan Kowalewski **"Specifying Life Cycle Requirements in natural Language and ptLTL"**
- 16:20 Werner Putschögl and Rudolf Ramler **"Reusing Automated Regression Tests for Multiple Variants of a Software Product Line"**
- 16:40 Bernhard Peischl and Sandra Lang **"What can we learn from in-process metrics on issue management?"**

17:00 - 17:30 Discussion and Closing